

Description

The μPD4368 is a high-speed 8,192-word by 8-bit static RAM designed with CMOS peripheral circuits and N-channel memory cells with polysilicon resistors. Two chip enable pins are provided for battery backup application, and an output enable pin is provided for easy interface.

The μPD4368 is packaged in 28-pin plastic DIP and 28-pin plastic SOJ packaging.

Features

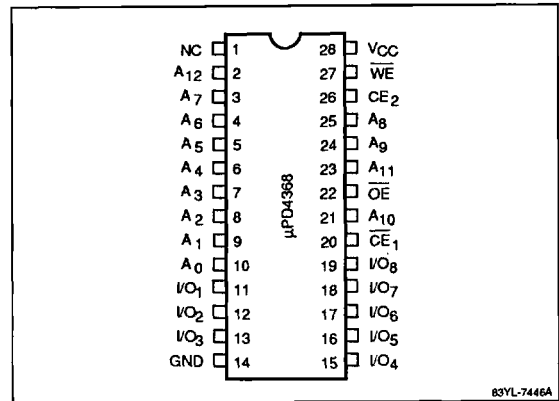
- 8,192 by 8-bit organization
- Single + 5-volt power supply
- Fully static operation—no clock or refreshing
- TTL-compatible inputs and outputs
- Common I/O using three-state outputs
- One OE and two CE pins for easy application
- Standard 28-pin plastic DIP, 28-pin plastic SOJ packaging

Ordering Information

Part Number	Access Time (max)	Package
μPD4368CR-15	15 ns	28-pin plastic DIP
CR-20	20 ns	
μPD4368LA-15	15 ns	28-pin plastic SOJ
LA-20	20 ns	

Pin Configuration

28-Pin Plastic DIP or SOJ

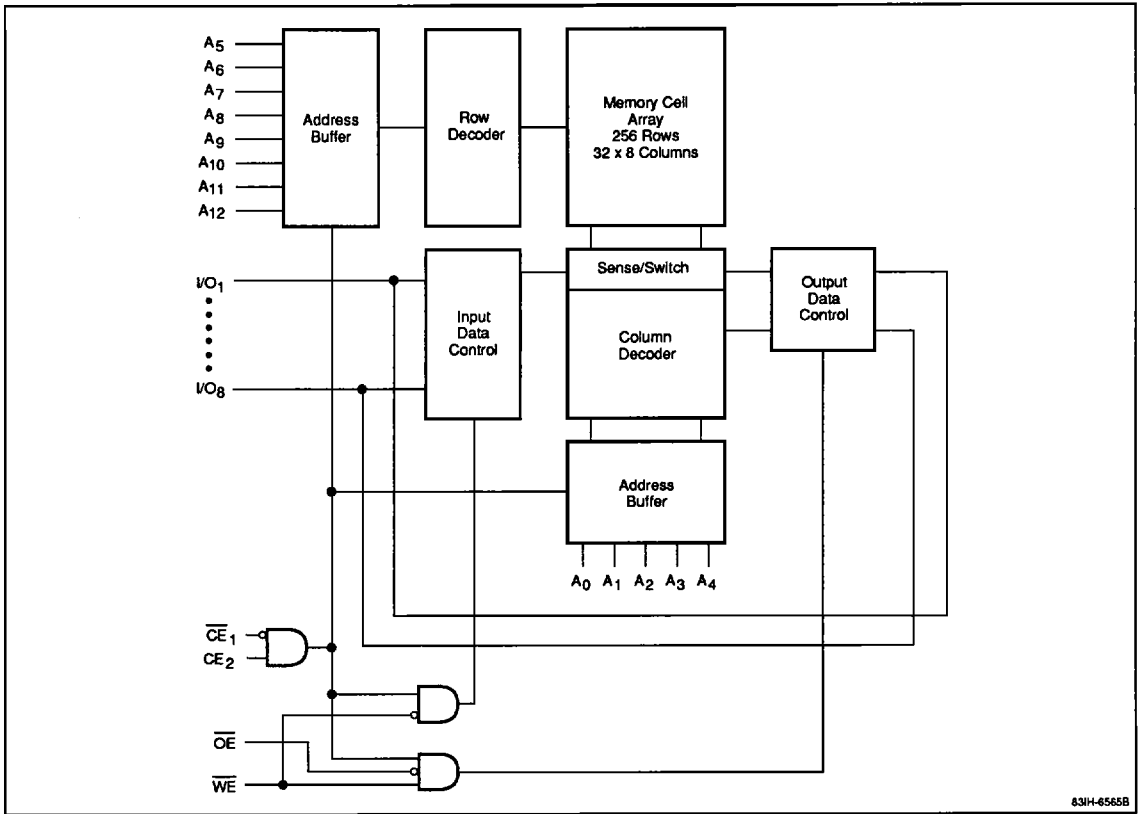


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Pin Identification

Symbol	Function
A ₀ - A ₁₂	Address inputs
I/O ₁ - I/O ₈	Data inputs/outputs
CE ₁	Chip enable (active low)
CE ₂	Chip enable (active high)
OE	Output enable
WE	Write enable
GND	Ground
V _{CC}	+ 5-volt power supply
NC	No connection

Block Diagram



Absolute Maximum Ratings

Supply voltage, V_{CC} (Note 1)	- 0.5 to +7.0 V
Input voltage, V_{IN} (Note 1)	- 0.5 V to $V_{CC} + 0.3$ V
Output voltage, V_{OUT} (Note 1)	- 0.5 V to $V_{CC} + 0.3$ V
Operating temperature, T_{OPR}	0 to +70°C
Storage temperature, T_{STG}	- 55 to +125°C
Power dissipation, P_D	1.0 W

Exposure to Absolute Maximum Ratings for extended periods may affect device reliability; exceeding the ratings could cause permanent damage. The device should be operated within the limits specified under DC and AC Characteristics.

Notes:

- (1) -3.0 V min for 10 ns maximum pulse.

Capacitance

$T_A = 25^\circ\text{C}$; $f = 1$ MHz; V_{IN} and $V_{OUT} = 0$ V

Parameter	Symbol	Min	Typ	Max	Unit
Input capacitance	C_{IN}			6	pF
Input/output capacitance	$C_{I/O}$			8	pF

DC Characteristics

$T_A = 0$ to +70°C; $V_{CC} = +5.0$ V $\pm 10\%$

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions
Input leakage current	I_{LI}	-2		2	μA	$V_{IN} = 0$ V to V_{CC}
Output leakage current	I_{LO}	-2		2	μA	$V_{IO} = 0$ V to V_{CC} ; $\overline{CE}_1 = V_{IH}$ or $CE_2 = V_{IL}$ or $\overline{OE} = V_{IH}$ or $\overline{WE} = V_{IL}$
Operating supply current	I_{CC}			120	mA	$\overline{CE}_1 = V_{IL}$; $CE_2 = V_{IH}$; $I_{I/O} = 0$ mA (min cycle)
Standby supply current	I_{SB}			20	mA	$\overline{CE}_1 \geq V_{IH}$ or $CE_2 = V_{IL}$
	I_{SB1}			2	mA	$\overline{CE}_1 \geq V_{CC} - 0.2$ V; $CE_2 \geq V_{CC} - 0.2$ V
Output voltage, low	V_{OL}			0.4	V	$I_{OL} = 8$ mA
Output voltage, high	V_{OH}	2.4			V	$I_{OH} = -4.0$ mA

Truth Table

Function	\overline{CE}_1	CE_2	\overline{OE}	\overline{WE}	I/O	I_{CC}
Not selected	H	X	X	X	High-Z	Standby
Not selected	X	L	X	X	High-Z	Standby
D_{OUT} disabled	L	H	H	H	High-Z	Active
Read	L	H	L	H	D_{OUT}	Active
Write	L	H	X	L	D_{IN}	Active

Recommended Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	4.5	5.0	5.5	V
Input voltage, high	V_{IH}	2.2		$V_{CC} + 0.3$	V
Input voltage, low	V_{IL}	-0.5		0.8	V
Operating temperature	T_A	0		70	°C

Notes:

- (1) $V_{IL} = -3.0$ V min for 10 ns maximum pulse.

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AC Characteristics

$T_A = 0$ to $+70^\circ\text{C}$; $V_{CC} = +5.0\text{V} \pm 10\%$

Parameter	Symbol	μPD4368-15		μPD4368-20		Unit	Test Conditions
		Min	Max	Min	Max		
Read Operation							
Read cycle time	t_{RC}	15		20		ns	
Address access time	t_{AA}		15		20	ns	
\overline{CE}_1 access time	t_{CO1}		15		20	ns	
CE_2 access time	t_{CO2}		15		20	ns	
Output enable to output valid	t_{OE}		9		10	ns	
Output hold from address change	t_{OH}	3		3		ns	
\overline{CE}_1 to output in low-Z	t_{LZ1}	3		3		ns	
CE_2 to output in low-Z	t_{LZ2}	3		3		ns	
\overline{OE} to output in low-Z	t_{OLZ}	0		0		ns	
\overline{CE}_1 to output in high-Z	t_{HZ1}		8		9	ns	
CE_2 to output in high-Z	t_{HZ2}		8		9	ns	
\overline{OE} to output in high-Z	t_{OHZ}		7		8	ns	
Write Operation							
Write cycle time	t_{WC}	15		20		ns	
Chip enable (\overline{CE}_1) to end of write	t_{CW1}	12		13		ns	
Chip enable (CE_2) to end of write	t_{CW2}	12		13		ns	
Address valid to end of write	t_{AW}	12		13		ns	
Address setup time	t_{AS}	0		0		ns	
Write pulse width	t_{WP}	11		12		ns	
Write recovery time	t_{WR}	2		2		ns	
Data valid to end of write	t_{DW}	9		10		ns	
Data hold time	t_{DH}	0		0		ns	
Write enable to output in high-Z	t_{WHZ}		7		8	ns	
Output active from end of write	t_{OW}	0		0		ns	

Notes:

- (1) Input pulse levels = 0.8 to 2.4 V; input pulse rise and fall times = 5 ns; timing reference level = 1.5 V; see figures 1 and 2 for output load.

Figure 1. Output Load
(t_{RC} , t_{AA} , t_{CO1} , t_{CO2} , t_{OE} , t_{OH})

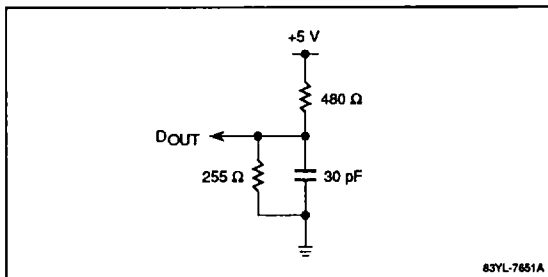
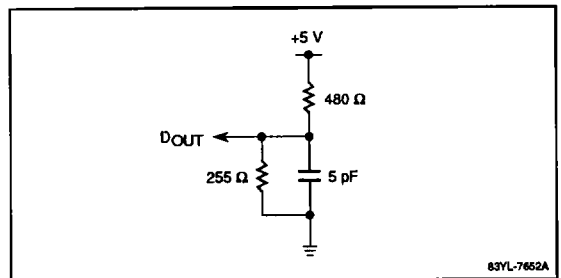
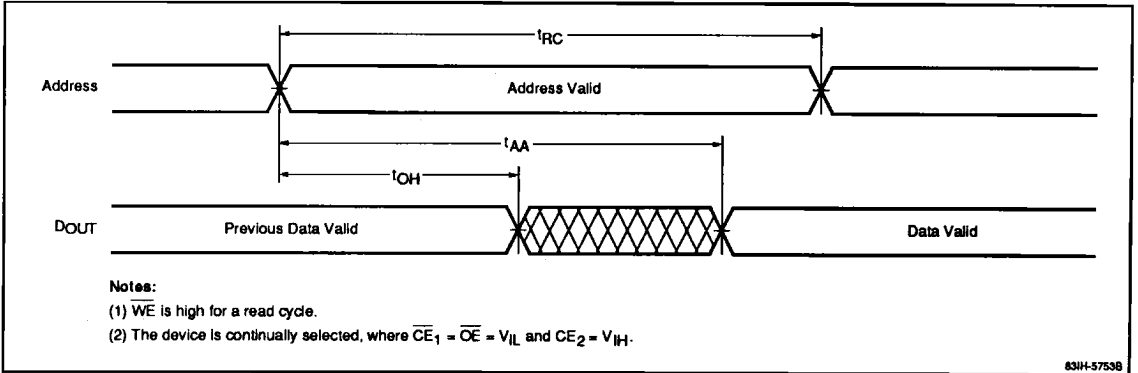


Figure 2. Output Load (t_{HZ1} , t_{HZ2} , t_{OHZ} , t_{WHZ} , t_{LZ1} , t_{LZ2} , t_{OLZ} , t_{OW})

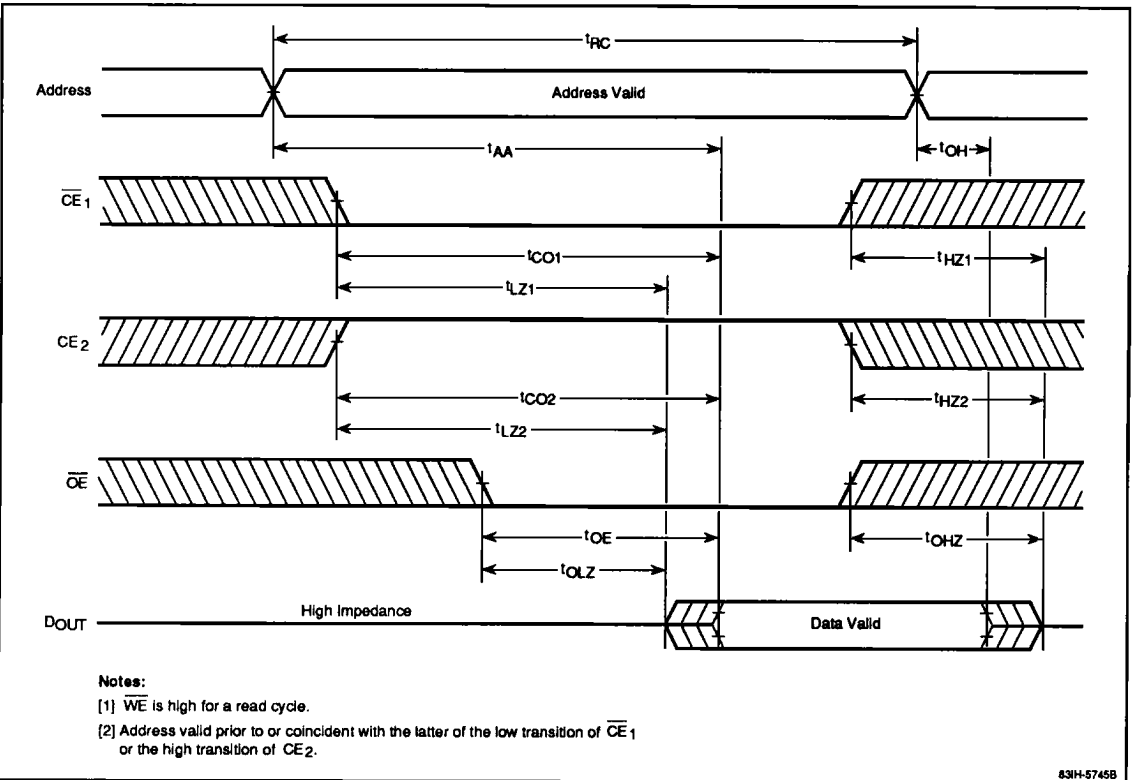


Timing Waveforms

Address Access Cycle



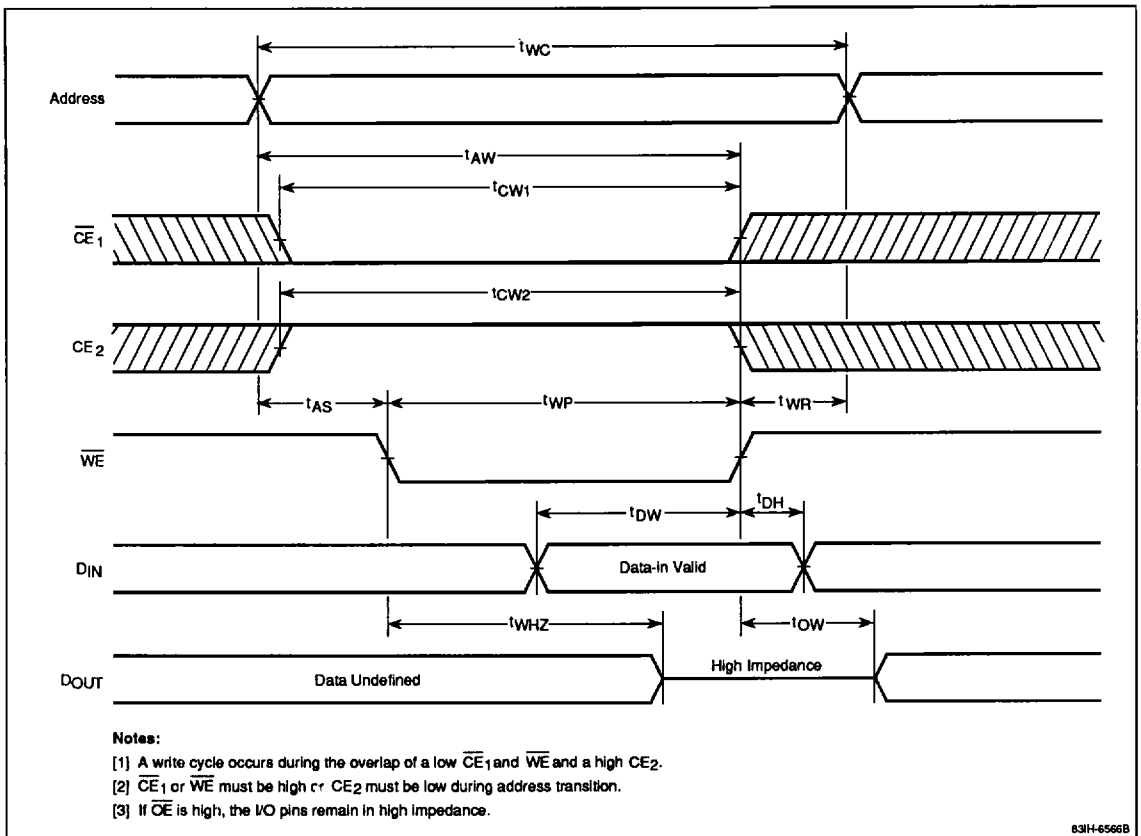
Chip Enable Access Cycle



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Timing Waveforms (cont)

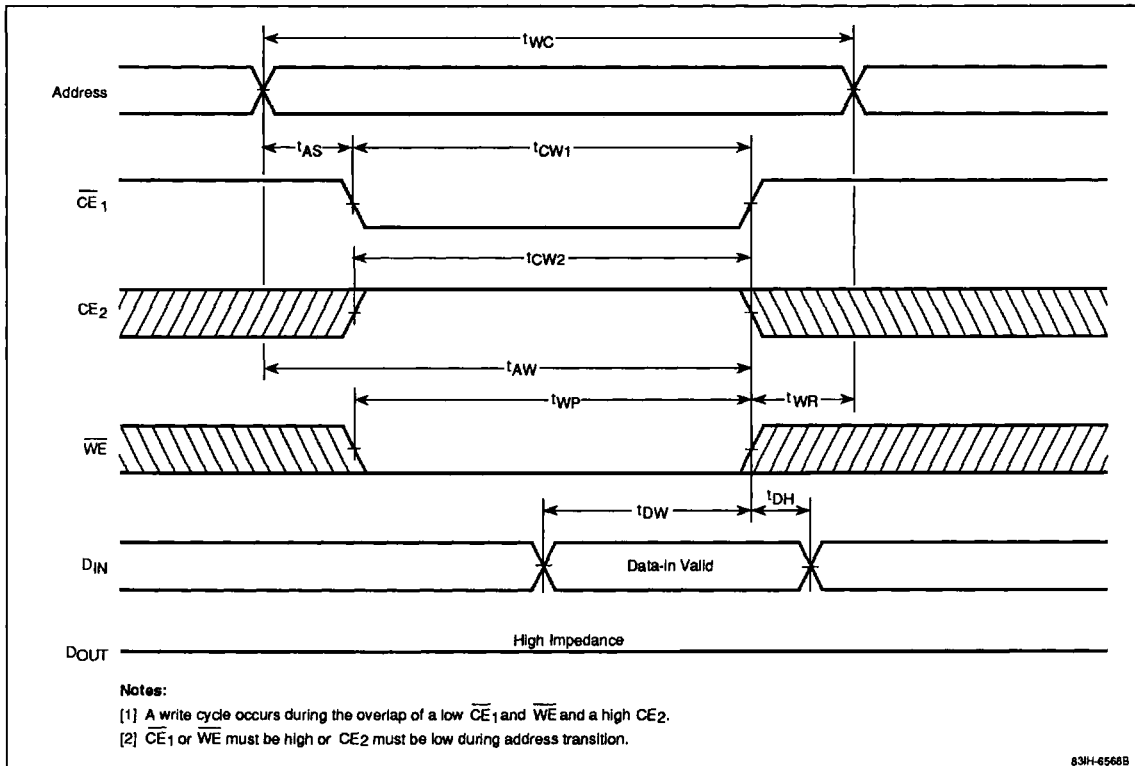
WE-Controlled Write Cycle



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Timing Waveforms (cont)

\overline{CE}_1 -Controlled Write Cycle



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Timing Waveforms (cont)

CE_2 -Controlled Write Cycle

